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Industrial Artificial Intelligence: Innovations and Challenges

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Deadline for manuscript submissions:

closed (30 April 2023)

Message from the Guest Editors

We look forward to receiving submissions of the latest research findings suggesting theories and practical solutions for various practical applications in industries based on artificial intelligence.

Authors are encouraged to submit contributions regarding the latest theories, methods, algorithms and applications of Al in:

- Controllable nuclear fusion;
- Nuclear power plants;
- Fluid machinery;
- Face recognition;
- Image and video recognition;
- Surface defect detection;
- Structural health monitoring;
- The quality inspection of the semiconductor industry;
- Industry monitoring based on fiber sensors;
- Other related areas.











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Message from the Editor-in-Chief

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